

CALL FOR INDUSTRY TRACK CONTRIBUTION

Submission Deadline Extended!

29th IEEE Asian Test Symposium (ATS 2020)

22-25 November 2020, Malaysia

(Virtual Conference)

<https://ieeemy.org/ats2020>

I apologize if there are multiple postings of this message. Based on the requests received, the organizing committee has decided to extend the paper submission deadline as follows.

Submission deadline (PDF paper):

August 17, 2020

IEEE Computer Society's Test Technology Technical Council (TTTC) and IEEE Council on Electronic Design Automation (CEDA) jointly organize the 29th IEEE ATS 2020. For the first time, ATS will be held as a **virtual conference** in Malaysia, on November 22-25, 2020.

The conference will be held in both synchronous and asynchronous formats. The synchronous event will be conducted for 4 days covering the tutorials, keynote talks, industry forums, invited talks and doctoral thesis award program. The technical paper presentations and industry paper presentations will be conducted as an asynchronous interactive event which will span outside of the 4-day program through our virtual conference platform. The registration fees to this virtual conference has also been updated on the website.

Industry practitioners are invited to submit original 1-page extended abstract on the innovative work and state-of-the-art experience to ats2020@easychair.org for presentation and publication in ATS 2020. Submission guidelines are provided at the conference website <https://ieeemy.org/ats2020>. I invite you to also share this call for papers with your colleagues.





ATS 2020 Sister Event

Workshop on RTL and High Level Testing (WRTLTL 2020)

In recognition of your support on contributing quality papers and participation in ATS, for the very first time, we include our sister event WRTLTL 2020 as part of ATS2020 technical programme exclusively for all the ATS2020 authors!

The workshop aims to encourage the presentation and discussion of truly innovative and "out-of-the-box" ideas aimed at addressing the challenges of high level test. We hope and expect this workshop will provide an ideal forum for discussion on this important topic for future system-on-a-chip (SoC) devices.

Keynote Speakers

ATS'20 Keynote	ATS'20 Keynote	ATS'20 Keynote	WRTLTL'20 Keynote
			
Dr Yervant Zorian Title: Robustness Challenges in the Internet of Things	Prof. Dr. Said Hamdioui Title: Computation-In-Memory Architectures based on NV devices: Opportunities and Challenges	Mr. Kam Heng Lee Vice President & General Manager, Intel Manufacturing Product Engineering (Malaysia) and High-Volume Engineering	Dr Davide Appello Title: Using SLT to Screen Automotive Products: Test the IC in the System before the System Tests your IC

Thank you.

Best regards,

Fawnizu Azmadi Hussin, PhD SMIEEE

General Chair, 29th IEEE Asian Test Symposium 2020 in Malaysia

Chair, IEEE Malaysia Section

<https://bit.ly/fawnizu> | fawnizu@ieee.org

Conference Website:

<https://ieeemy.org/ats2020>